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U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
		2003/0169672	09/2003	Onoe et al.			
		2004/0047245	03/2004	Onoe et al.			
		2004/0246879	12/2004	Onoe et al.			
		5,864,445	01/1999	Bennin et al.			
		6,418,091	07/2002	Hirokane et al.			
		7,020,064	03/2006	Kim et al.			

FOREIGN PATENT DOCUMENTS

		DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES	TRANSLATION NO
		1 351 939	05/1974	GB				
		55 139643	10/1980	JP			ABSTRACT	
		59-22250	02/1984	JP			ABSTRACT	
		63-001175	01/1988	JP			ABSTRACT	
		06-267122	09/1994	JP			ABSTRACT	
		08-212604	08/1996	JP				
		09-097457	04/1997	JP			ABSTRACT	
		09-153235	06/1997	JP			ABSTRACT	
		09-222430	08/1997	JP			ABSTRACT	
		10-334525	12/1998	JP			ABSTRACT	
		11-045467	02/1999	JP			ABSTRACT	
		11-176033	07/1999	JP			ABSTRACT	
		1 333 436	08/2003	EP				
		1 369 864	12/2003	EP				
		1 381 042	01/2004	EP				
		1 398 779	03/2004	EP				
		1 398 780	03/2004	EP				

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